

Search Notes

Application/Control No.

10/776,278

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

MARUYAMA ET AL.

Art Unit

1792

SEARCHED

Class	Subclass	Date	Examiner
427	64	6/4/2008	BT
427	67	6/4/2008	BT
427	427.1	6/4/2008	BT
427	427.2	6/4/2008	BT
427	427.6	6/4/2008	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text search using databases in EAST	6/4/2008	BT